LogicVision

LogicVision is developing a hierarchical, integrated Built-in-Self-Test (BIST) methodology and associated tools for printed circuit board, multichip module, and system-level test. The methodology and tool sets are developed as a part of the RASSP Technology Base.

Focus on RASSP

BIST enables at-speed test and less dependence on external testing. LogicVision is identifying major building blocks that can be embedded as application-specific integrated circuits (ASICs) or other off-the-shelf components, then developing an autonomously testable BIST device solution. The solutions will take into account standard protocols (1149.X) and diagnosis procedures. The key advantages of HIBIST are its reduced time to market, reusability, and quality. Alta Group is helping with the integration of autonomously testable BIST and HIBIST into their design environment.
Automation is the key to achieve productivity in the design and manufacturing process. It is required at various levels of the design capture process and physical packaging hierarchy. This automation aspect is an integral aspect of autonomously testable BIST and HIBIST. Automation will enable the top-down specification of test features and the bottom-up reuse of test information at various package levels.

For More Information
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